Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/768,727	RIPPICH, ANDREAS	
Examiner	Art Unit	
Joon H. Hwang	2162	

SEARCHED					
Class	Subclass	Date	Examiner		
			<u>.</u> .		

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
PGPUB and USPAT text search-see search history printouts		8/12/2005	JH		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
see search history printout(s) Inventor searched consulted 101 help panel ACM, IEEE consulted John Breene	8/1/2005	. JH
consulted Charles Rones consulted Greta Robinson consulted Mohammad Ali consulted Jean Corrielus	8/1/2005	JH
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